

<b>Notice of References Cited</b>	Application/Control No. 10/624,759	Applicant(s)/Patent Under Reexamination WEN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,349,296	02-2002	Broder et al.	707/3
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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